

Notice of References Cited	Application/Control No. 09/688,766	Applicant(s)/Patent Under Reexamination MORIKAWA ET AL.	
	Examiner Russell Frejd	Art Unit 2128	Page 1 of 2

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	C	US-6,600,965	07-2003	Hull et al.	700/120
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Russell Frejd	Art Unit 2128	Page 2 of 2

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